

Notice of References Cited	Application/Control No. 10/580,664		Applicant(s)/Patent Under Reexamination LIN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0042926 A1	03-2004	Shimizu, Yoshiyuki	420/038
*	B	US-6,488,784 B1	12-2002	Fortunati et al.	148/308
*	C	US-6,110,298 A	08-2000	Senda et al.	148/308
*	D	US-6,103,022 A	08-2000	Komatsubara et al.	148/308
*	E	US-5,614,034 A	03-1997	Suga et al.	148/111
*	F	US-5,512,110 A	04-1996	Yoshitomi et al.	148/113
*	G	US-5,200,145 A	04-1993	Krutenat et al.	420/129
*	H	US-4,576,658	03-1986	Inokuti et al.	148/111
*	I	US-4,212,689	07-1980	Shimizu et al.	148/111
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2002-275601	09-2002	Japan	-----	----
	O	61-9521	01-1986	Japan	Iguchi et al.	----
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	ASM Materials Engineering Dictionary, 1992, page 211.			
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.